

**Features**

- Low Power Standby . . . . . **275 $\mu$ W Max**
- Low Power Operation . . . . . **55mW/MHz Max**
- Fast Access Time. . . . . **120/200ns Max**
- Industry Standard Pinout
- Single Supply . . . . . **5.0V V<sub>CC</sub>**
- TTL Compatible
- Static Memory Cells
- High Output Drive
- On-Chip Address Latches
- Easy Microprocessor Interfacing

**Description**

The HM-6516 is a CMOS 2048 x 8 Static Random Access Memory. Extremely low power operation is achieved by the use of complementary MOS design techniques. This low power is further enhanced by the use of synchronous circuit techniques that keep the active (operating) power low, which also gives fast access times. The pinout of the HM-6516 is the popular 24 pin, 8-bit wide JEDEC standard, which allows easy memory board layouts, flexible enough to accommodate a variety of PROMs, RAMS, EPROMs, and ROMs.

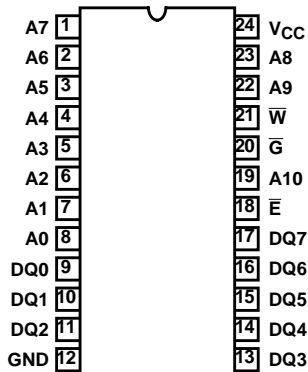
The HM-6516 is ideally suited for use in microprocessor based systems. The byte wide organization simplifies the memory array design, and keeps operating power down to a minimum, because only one device is enabled at a time. The address latches allow very simple interfacing to recent generation microprocessors which employ a multiplexed address/data bus. The convenient output enable control also simplifies multiplexed bus interfacing by allowing the data outputs to be controlled independent of the chip enable.

**Ordering Information**

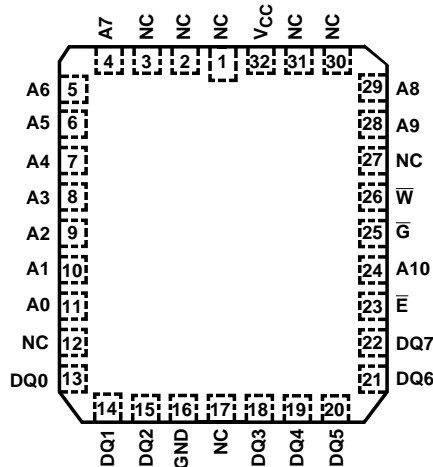
120ns	200ns	TEMP. RANGE	PACKAGE	PKG. NO.
HM1-6516B-9	HM1-6516-9	-40°C to +85°C	CERDIP	F24.6
-	29102BJA	-55°C to +125°C	JAN#	F24.6
8403607JA	8403601JA	-55°C to +125°C	SMD#	F24.6
-	HM4-6516-9	-40°C to +85°C	CLCC	J32.A
8403607ZA	8403601ZA	-55°C to +125°C	SMD#	J32.A

**Pinouts**

**HM-6516  
(CERDIP)  
TOP VIEW**

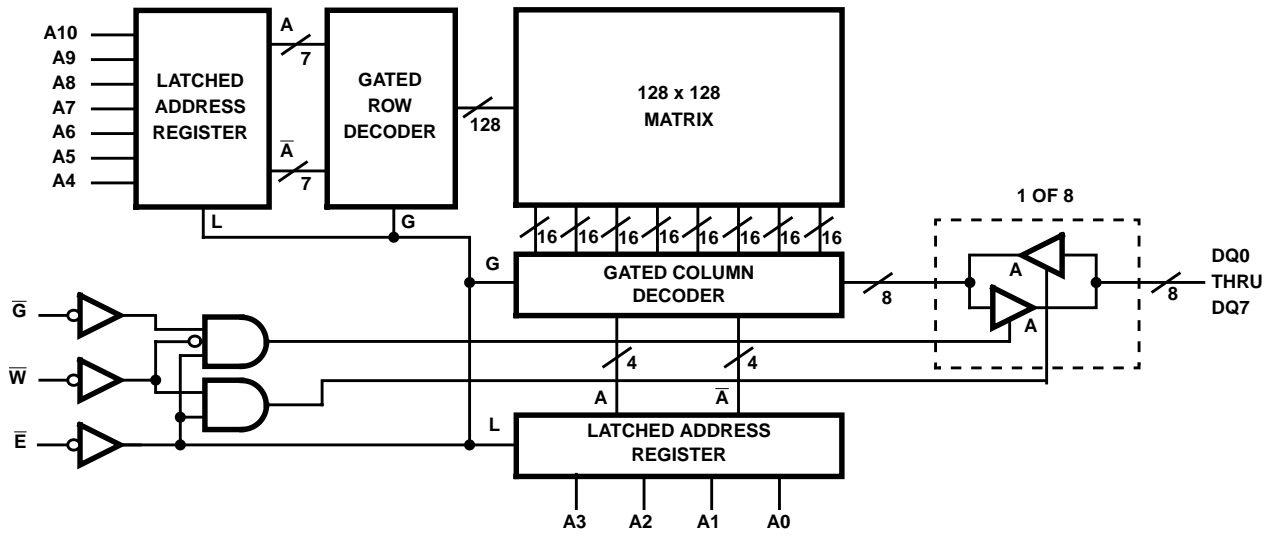


**HM-6516  
(CLCC)  
TOP VIEW**



PIN	DESCRIPTION
NC	No Connect
A0 - A10	Address Inputs
$\bar{E}$	Chip Enable/Power Down
V <sub>SS</sub> /GND	Ground
DQ0 - DQ7	Data In/Data Out
V <sub>CC</sub>	Power (+5V)
$\bar{W}$	Write Enable
$\bar{G}$	Output Enable

Functional Diagram



# HM-6516

## Absolute Maximum Ratings

Supply Voltage ..... +7.0V  
 Input or Output Voltage Applied for all Grades ..... GND -0.3V to  $V_{CC} + 0.3V$   
 ESD Classification ..... Class 1

## Operating Conditions

Operating Voltage Range ..... +4.5V to +5.5V  
 Operating Temperature Ranges:  
 HM-6516B-9, HM-6516-9 ..... -40°C to +85°C

## Thermal Information

Thermal Resistance  
 CERDIP Package .....  $\theta_{JA}$  48°C/W  $\theta_{JC}$  8°C/W  
 CLCC Package ..... 66°C/W 12°C/W  
 Maximum Storage Temperature Range ..... -65°C to +150°C  
 Maximum Junction Temperature ..... +175°C  
 Maximum Lead Temperature (Soldering 10s) ..... +300°C

## Die Characteristics

Gate Count ..... 25953 Gates

*CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.*

## DC Electrical Specifications $V_{CC} = 5V \pm 10\%$ ; $T_A = -40^\circ C$ to $+85^\circ C$ (HM-6516B-9, HM-6516-9)

SYMBOL	PARAMETER	LIMITS		UNITS	TEST CONDITIONS
		MIN	MAX		
ICCSB	Standby Supply Current	-	50	$\mu A$	$I_O = 0mA$ , $V_I = V_{CC}$ or GND, $V_{CC} = 5.5V$ , HM-6516B-9
		-	100	$\mu A$	$I_O = 0mA$ , $V_I = V_{CC}$ or GND, HM-6516-9
ICCOP	Operating Supply Current (Note 1)	-	10	mA	$f = 1MHz$ , $I_O = 0mA$ , $\bar{G} = V_{CC}$ , $V_{CC} = 5.5V$ , $V_I = V_{CC}$ or GND
ICCDR	Data Retention Supply Current	-	25	$\mu A$	$V_{CC} = 2.0V$ , $I_O = 0mA$ , $V_I = V_{CC}$ or GND, $\bar{E} = V_{CC}$ , HM-6516B-9
		-	50	$\mu A$	$V_{CC} = 2.0V$ , $I_O = 0mA$ , $V_I = V_{CC}$ or GND, $\bar{E} = V_{CC}$ , HM-6516-9
VCCDR	Data Retention Supply Voltage	2.0	-	V	
II	Input Leakage Current	-1.0	+1.0	$\mu A$	$V_I = V_{CC}$ or GND, $V_{CC} = 5.5V$
IIOZ	Input/Output Leakage Current	-1.0	+1.0	$\mu A$	$V_{IO} = V_{CC}$ or GND, $V_{CC} = 5.5V$
$V_{IL}$	Input Low Voltage	-0.3	0.8	V	$V_{CC} = 4.5V$
$V_{IH}$	Input High Voltage	2.4	$V_{CC} + 0.3$	V	$V_{CC} = 5.5V$
VOL	Output Low Voltage	-	0.4	V	$I_O = 3.2mA$ , $V_{CC} = 4.5V$
VOH1	Output High Voltage	2.4	-	V	$I_O = -1.0mA$ , $V_{CC} = 4.5V$
VOH2	Output High Voltage (Note 2)	$V_{CC} - 0.4$	-	V	$I_O = -100\mu A$ , $V_{CC} = 4.5V$

## Capacitance $T_A = +25^\circ C$

SYMBOL	PARAMETER	MAX	UNITS	TEST CONDITIONS
CI	Input Capacitance (Note 2)	8	pF	$f = 1MHz$ , All measurements are referenced to device GND
CIO	Input/Output Capacitance (Note 2)	10	pF	

### NOTES:

1. Typical derating 5mA/MHz increase in ICCOP.
2. Tested at initial design and after major design changes.

## HM-6516

### AC Electrical Specifications $V_{CC} = 5V \pm 10\%$ ; $T_A = -40^{\circ}C$ to $+85^{\circ}C$ (HM-6516B-9, HM-6516-9)

SYMBOL	PARAMETER	LIMITS				UNITS	TEST CONDITIONS
		HM-6516B-9		HM-6516-9			
		MIN	MAX	MIN	MAX		
(1) TELQV	Chip Enable Access Time	-	120	-	200	ns	(Notes 1, 3)
(2) TAVQV	Address Access Time	-	120	-	200	ns	(Notes 1, 3, 4)
(3) TELQX	Chip Enable Output Enable Time	10	-	10	-	ns	(Notes 2, 3)
(4) TWLQZ	Write Enable Output Disable Time	-	50	-	80	ns	(Notes 2, 3)
(5) TEHQZ	Chip Enable Output Disable Time	-	50	-	80	ns	(Notes 2, 3)
(6) TGLQV	Output Enable Output Valid Time	-	80	-	80	ns	(Notes 1, 3)
(7) TGLQX	Output Enable Output Enable Time	10	-	10	-	ns	(Notes 2, 3)
(8) TGHQZ	Output Enable Output Disable Time	-	50	-	80	ns	(Notes 2, 3)
(9) TELEH	Chip Enable Pulse Negative Width	120	-	200	-	ns	(Notes 1, 3)
(10) TEHEL	Chip Enable Pulse Positive Width	50	-	80	-	ns	(Notes 1, 3)
(11) TAVEL	Address Setup Time	0	-	0	-	ns	(Notes 1, 3)
(12) TELAX	Address Hold Time	30	-	50	-	ns	(Notes 1, 3)
(13) TWLWH	Write Enable Pulse Width	120	-	200	-	ns	(Notes 1, 3)
(14) TWLEH	Write Enable Pulse Setup Time	120	-	200	-	ns	(Notes 1, 3)
(15) TELWH	Write Enable Pulse Hold Time	120	-	200	-	ns	(Notes 1, 3)
(16) TDVWH	Data Setup Time	50	-	80	-	ns	(Notes 1, 3)
(17) TWHDX	Data Hold Time	10	-	10	-	ns	(Notes 1, 3)
(18) TELEL	Read or Write Cycle Time	170	-	280	-	ns	(Notes 1, 3)

**NOTES:**

1. Input pulse levels: 0.8V to  $V_{CC} - 2.0V$ ; Input rise and fall times: 5ns (max); Input and output timing reference level: 1.5V; Output load: 1 TTL gate equivalent,  $C_L = 50pF$  (min) - for  $C_L$  greater than 50pF, access time is derated by 0.15ns per pF.
2. Tested at initial design and after major design changes.
3.  $V_{CC} = 4.5V$  and 5.5V.
4. TAVQV = TELQV + TAVEL.

Timing Waveforms

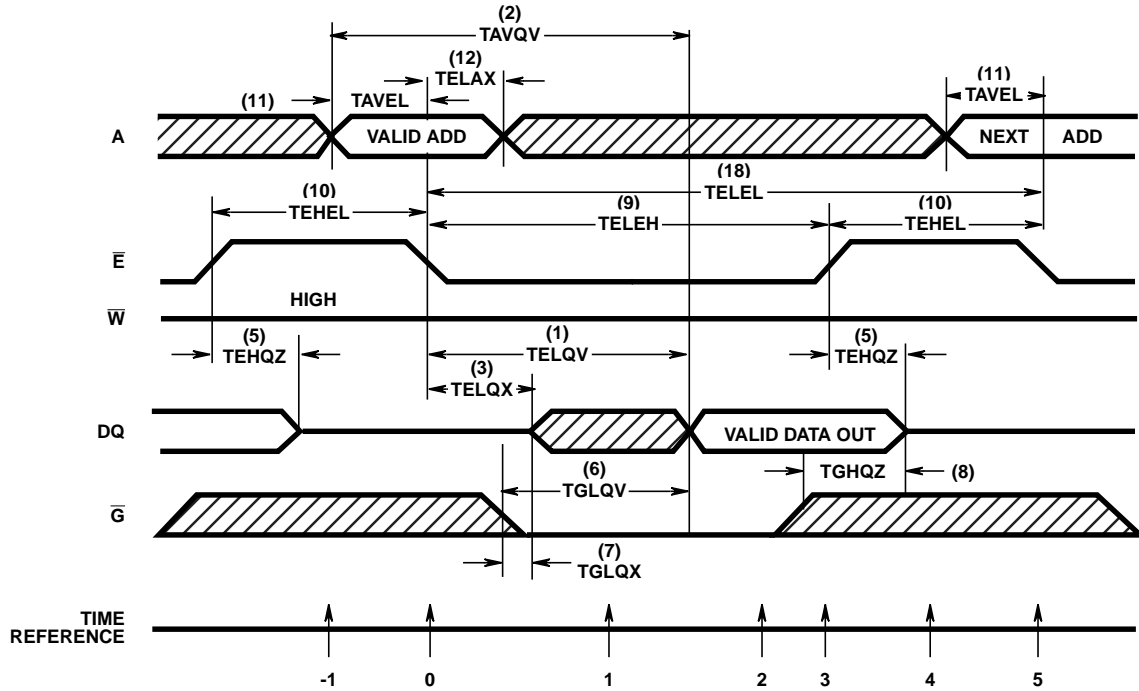


FIGURE 1. READ CYCLE

The address information is latched in the on-chip registers on the falling edge of  $\bar{E}$  ( $T = 0$ ), minimum address setup and hold time requirements must be met. After the required hold time, the addresses may change state without affecting device operation. During time ( $T = 1$ ), the outputs become enabled but data is not valid until time ( $T = 2$ ),  $\bar{W}$  must

remain high throughout the read cycle. After the data has been read,  $\bar{E}$  may return high ( $T = 3$ ). This will force the output buffers into a high impedance mode at time ( $T = 4$ ).  $\bar{G}$  is used to disable the output buffers when in a logical "1" state ( $T = -1, 0, 3, 4, 5$ ). After ( $T = 4$ ) time, the memory is ready for the next cycle.

Timing Waveforms (Continued)

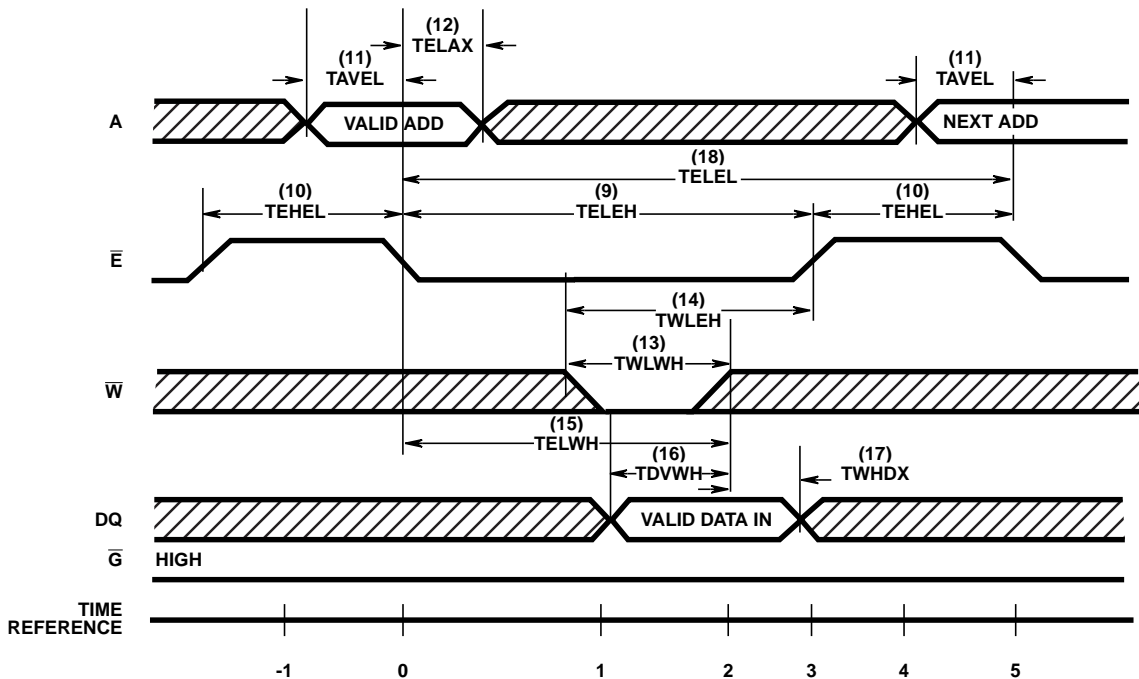


FIGURE 2. WRITE CYCLE

## HM-6516

The write cycle is initiated on the falling edge of  $\bar{E}$  ( $T = 0$ ), which latches the address information in the on-chip registers. If a write cycle is to be performed where the output is not to become active,  $\bar{G}$  can be held high (inactive). TDVWH and TWHDX must be met for proper device operation regardless of  $\bar{G}$ . If  $\bar{E}$  and  $\bar{G}$  fall before  $\bar{W}$  falls (read mode), a possible bus conflict may exist. If  $\bar{E}$  rises before  $\bar{W}$

rises, reference data setup and hold times to the  $\bar{E}$  rising edge. The write operation is terminated by the first rising edge of  $\bar{W}$  ( $T = 2$ ) or  $\bar{E}$  ( $T = 3$ ). After the minimum  $\bar{E}$  high time (TEHEL), the next cycle may begin. If a series of consecutive write cycles are to be performed, the  $\bar{W}$  line may be held low until all desired locations have been written. In this case, data setup and hold times must be referenced to the rising of  $\bar{E}$ .

### Typical Performance Curve

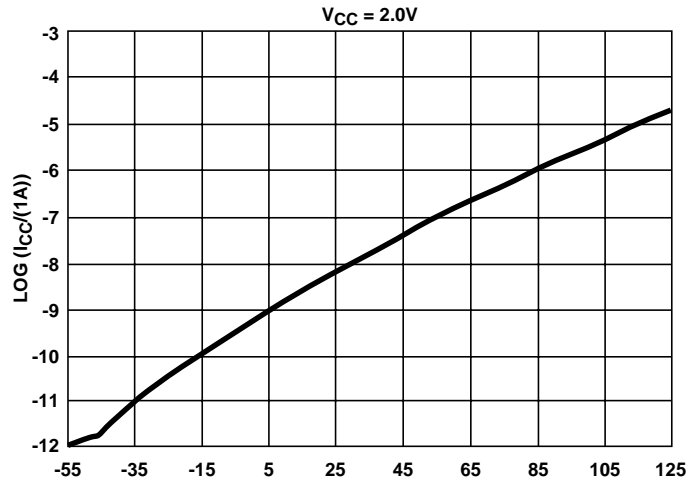


FIGURE 3. TYPICAL ICCDR vs T<sub>A</sub>

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### Sales Office Headquarters

#### NORTH AMERICA

Intersil Corporation  
P. O. Box 883, Mail Stop 53-204  
Melbourne, FL 32902  
TEL: (407) 724-7000  
FAX: (407) 724-7240

#### EUROPE

Intersil SA  
Mercure Center  
100, Rue de la Fusee  
1130 Brussels, Belgium  
TEL: (32) 2.724.2111  
FAX: (32) 2.724.22.05

#### ASIA

Intersil (Taiwan) Ltd.  
Taiwan Limited  
7F-6, No. 101 Fu Hsing North Road  
Taipei, Taiwan  
Republic of China  
TEL: (886) 2 2716 9310  
FAX: (886) 2 2715 3029